

- HW-1 4
- Some answers for Pb. 4 "Understanding figures of merit for beamlines."

The overall performance, which considers the signal-to-noise ratio of the experiments within the resolution window set by the optical setup of the beamline should be the brilliance \bullet R brightness in 6 D.

However, usually transverse phase space may be decoupled from the longitudinal one, so may consider 4D Brightness (B_{4D}) and longitudinal one separately. Here are what matter in each category of applications:

- (i) Diffraction: The spatial resolution is defined by coherent superposition of electron waves. Hence coherence length is most important. So given the ~~constant~~ ^{same} brightness, the optimization should be for L_x ^{obtained} and may achieve short at independently.
- (ii) Scanning microscopy: signal ^{from inelastic scattering} over focused beam ^{footprint} ~~area~~, rastered along the surface. Hence, the spatial resolution is accomplished by minimizing Δr , despite of increasing Δd , short at possible within space-charge limit.
- (iii) Imaging: in coherent imaging mode, resolution is limited by the contrast ~~and~~ modulation transfer functions, which is diffraction-limited. Hence high coherence length L_x is the objective. But avoid the space-charge effect, by bunching moderately.
- (iv) Spectroscopy: This mainly involves longitudinal dimension. The optimization is small ΔE while compromising Δt .
- (v) For X-FEL generation at undulator sector, coherent electrons with high bunch charges N_e ^($\Delta E, \Delta t$ small) are of high importance.